

AMENDMENTS TO THE SPECIFICATION

Please amend paragraph [0022] at page 6 of the specification as follows:

[0022] While the light 22 transmitting to the liquid crystal layer of the PDLC 14 is reflected on the reflection sheet 16 and is reverse directed to a light path, the light 22 scattered in the liquid crystal layer of the PDLC 14 nearly vanishes and is not nearly incident to the reflection sheet 16. The light reflected in the modulator 10 is received to a charge-coupled device (CCD) (not shown) via the lens 21 and then is converted to an electrical signal. The received signal converted electrically is then transferred to a display apparatus (not shown) via a signal processing circuit. A testing inspector monitors an image or data displayed in the display apparatus to determine whether it is bad or not. The testing inspector secondarily performs a close inspection of doubtful points the signal **(data and gate)** wires 17 and 18.

Please amend paragraph [0061] at page 15 of the specification as follows:

[0061] The odd-numbered signal wires 401, 403, ..., 40n-1 are connected to a first shorting wire 43a on one side to make a short circuit that is electrically isolated from even-signal wires 402, 404,..., 40n. The first shorting wire 43a connects to a first inspection pad 41a supplied with the high common voltage V_h . The even-signal wires 402, 404, ..., 40n connect to a second **shorted shorting** wire 43b on one side to make a short circuit electrically isolated from odd-signal wires

401, 403, ..., 40n-1. The second shorting wire 43b is connected to a second inspection pad 41b supplied with a low common voltage V_l.

Please amend paragraph [00102] at pages 26-27 of the specification as follows:

[00102] As described above, the inspection method and apparatus for a flat display device according to the invention scans the magnetic sensor on the signal wires along the scan direction crossing the signal wires, or proceeds in a zig-zag pattern between the adjacent signal wires. ~~s-a~~ As a result, the inspection method and the apparatus of the flat display apparatus according to the invention may rapidly and exactly finds defects such as a short circuit or an open circuit of the signal wire.